

## Terminating F100K ECL Inputs

### Introduction

Many F100K designs require that certain inputs be presented with a HIGH or LOW level. Because of the construction of the F100K input circuitry, a LOW can be realized by simply leaving the input OPEN. However, a HIGH must be terminated in a special way. Simply tying the input to  $V_{CC}/V_{CCA}$  is unacceptable.

### Design Considerations

The ranges of  $V_{IH}$  and  $V_{IL}$  across  $V_{EE}$  ( $-4.2V$  to  $-5.7V$  for F100K ECL 300 Series) are  $-870$  mV to  $-1165$  mV and  $-1475$  mV to  $-1830$  mV respectively. By staying within these ranges, proper input conditions are assured. Figure 1 shows the voltage versus current for the F100K input transistor. If the input is tied to  $V_{CC}/V_{CCA}$  the input transistor saturates (Point D) which can damage internal circuitry. The best  $V_{IH}$  to realize a HIGH is a voltage drop of  $0.9V$  below  $V_{CC}/V_{CCA}$ . As can be seen from the graph, this locates the quiescent point on the flat part of the curve (Point C) midway within the acceptable range of  $V_{IH}$ . Figure 2 shows three ways in which a HIGH can be realized on the input. These circuits allow the user to maintain constant input signals at optimum levels of  $V_{EE}$  and temperature. Each circuit can handle multiple fanouts, the number will depend upon the maximum current capability of the cir-

cuit. The designer should be aware that although Figure 2A, Figure 2B, and Figure 2C supply ECL compatible signals levels, they differ in power consumption and susceptibility to changes in temperature and  $V_{EE}$ .

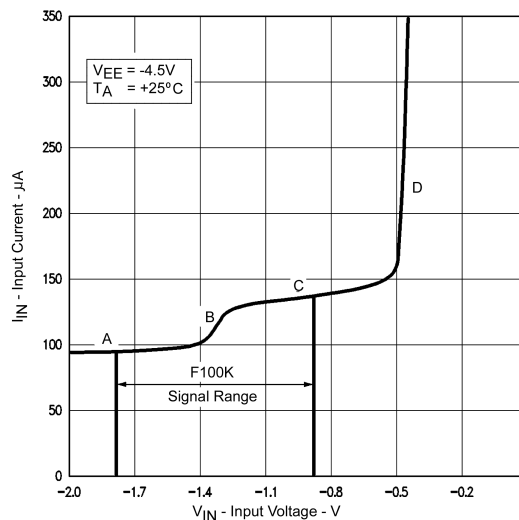
For designs where there are multiple unused inputs and extra logic gates available, fanout from the unused gates is possible. As an example, one gate of the 100302 is capable of driving ten quiescent inputs at voltage and current levels typical of F100K as shown in Figure 3.

Figure 4 shows in detail the F100K pull-up scheme and the input circuitry. Although the circuits of Figure 2 are good examples, a detailed circuit analysis must include the  $50$  k $\Omega$  input resistor. In Figure 4A, the resistor ( $R_D$ ) which sets the diode biasing current is in parallel with the  $50$  k $\Omega$  input resistor. Similarly, the circuit of Figure 4B shows that  $R_2$  is in parallel with the input resistor.

The point to emphasize is never tie an F100K input to  $V_{CC}/V_{CCA}$  in order to realize a HIGH preset. Instead, the following is recommended:

- For a LOW level — leave input open or tie to  $V_{EE}$ .
- For a HIGH level — tie input to a diode drop or  $0.9V$  below  $V_{CC}/V_{CCA}$ .

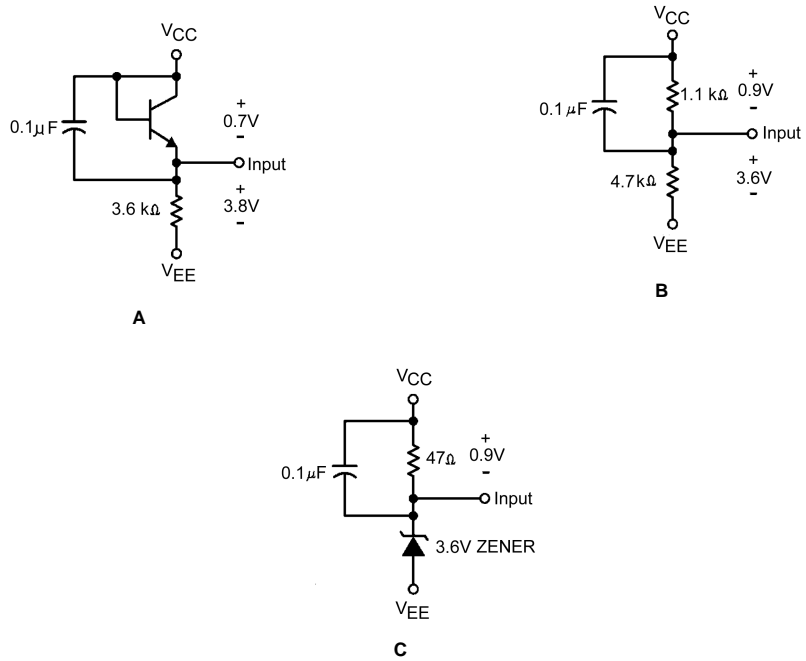
Remember also that the  $50$  k $\Omega$  input resistor must be considered in the circuit parameter calculations.



A =  $50$  k $\Omega$  Pull-Down Current  
B = Transition (Switching) Region  
C = Base Current plus  $50$  k $\Omega$   
D = Input Transistor Saturation

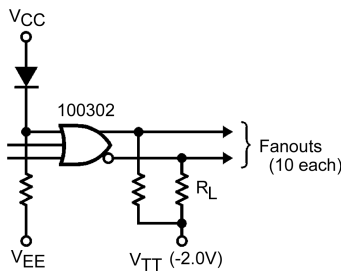
FIGURE 1. Input Characteristics

**Design Considerations** (Continued)



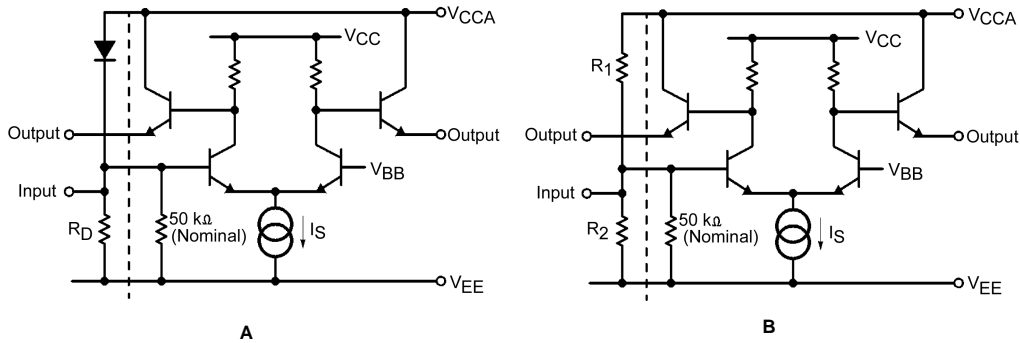
Note: Nominal values are shown.

**FIGURE 2. Equivalent Circuits for HIGH Termination**



**FIGURE 3. Utilizing Unused Gates to Terminate Multiple HIGHs and LOWs**

**Design Considerations** (Continued)



**FIGURE 4. Pull-Up Circuit Examples**

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